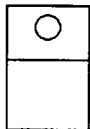


N-Channel Enhancement-Mode Transistor

Product Summary

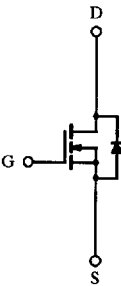
$V_{(BR)DSS}$ (V)	$r_{DS(on)}$ (Ω)	I_D (A)
200	0.10	28

TO-254AA
Hermetic Package



Case Isolated

D S G
Top View



N-Channel MOSFET

Absolute Maximum Ratings ($T_C = 25^{\circ}\text{C}$ Unless Otherwise Noted)

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V_{DS}	200	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current ($T_J = 150^{\circ}\text{C}$)	$T_C = 25^{\circ}\text{C}$	I_D	28	A
	$T_C = 100^{\circ}\text{C}$		18	
Pulsed Drain Current		I_{DM}	112	
Maximum Power Dissipation	$T_C = 25^{\circ}\text{C}$	P_D	150	W
	$T_C = 100^{\circ}\text{C}$		60	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	-55 to 150	$^{\circ}\text{C}$
Lead Temperature ($1/16''$ from case for 10 sec.)		T_L	300	

6
N-/P-Channel
MOSFETs

Thermal Resistance Ratings

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient	R_{thJA}		50	$^{\circ}\text{C/W}$
Maximum Junction-to-Case	R_{thJC}		0.83	
Case-to-Sink	R_{thCS}	0.2		

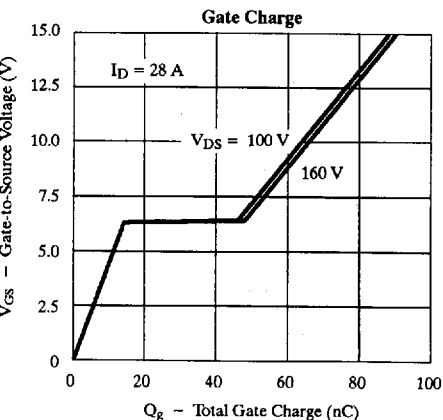
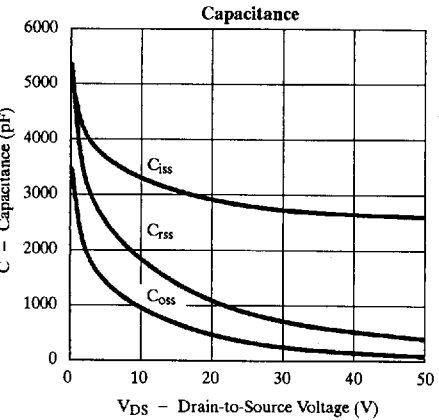
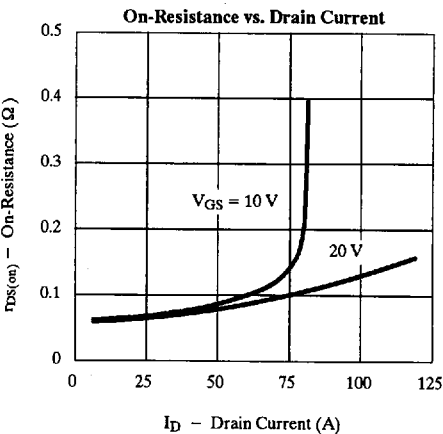
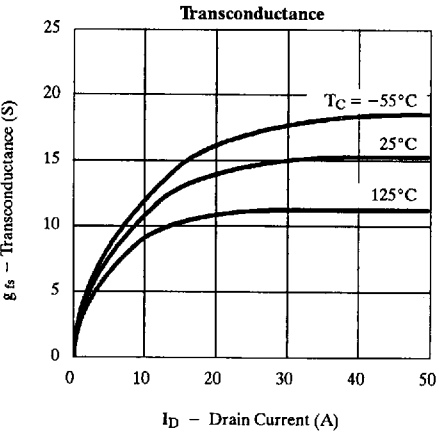
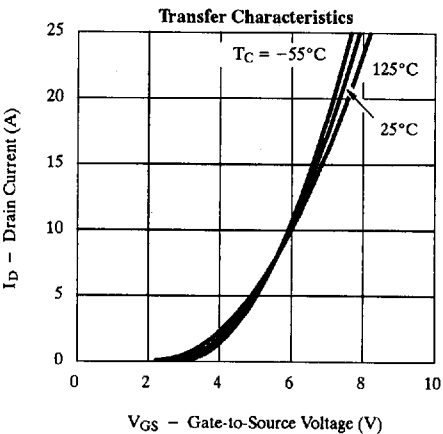
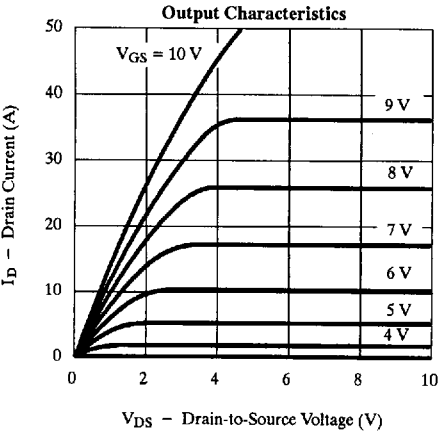
Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Limit			Unit
			Min	Typ ^a	Max	
Static						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA	200			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.0	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 160 V, V _{GS} = 0 V			25	μA
		V _{DS} = 160 V, V _{GS} = 0 V, T _J = 125°C			250	
On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	28			A
Drain-Source On-State Resistance ^b	r _{DS(on)}	V _{GS} = 10 V, I _D = 18 A		0.080	0.10	Ω
		V _{GS} = 10 V, I _D = 18 A, T _J = 125°C		0.15	0.17	
Forward Transconductance ^b	g _{fs}	V _{DS} = 15 V, I _D = 18 A	9.0	12	27	S
Dynamic						
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz		2700		pF
Output Capacitance	C _{oss}			850		
Reverse Transfer Capacitance	C _{rss}			300		
Total Gate Charge ^c	Q _g	V _{DS} = 100 V, V _{GS} = 10 V, I _D = 28 A		63	115	nC
Gate-Source Charge ^c	Q _{gs}			14	21	
Gate-Drain Charge ^c	Q _{gd}			32	60	
Turn-On Delay Time ^c	t _{d(on)}	V _{DD} = 100 V, R _L = 3.6 Ω I _D ≅ 28 A, V _{GEN} = 10 V, R _G = 2.4 Ω		15	35	ns
Rise Time ^c	t _r			100	150	
Turn-Off Delay Time ^c	t _{d(off)}			70	125	
Fall Time ^c	t _f			50	100	
Source-Drain Diode Ratings and Characteristics						
Continuous Current	I _S				28	A
Pulsed Current	I _{SM}				112	
Diode Forward Voltage ^b	V _{SD}	I _F = 28 A, V _{GS} = 0 V	0.6		1.8	V
Reverse Recovery Time	t _{rr}	I _F = 28 A, di/dt = 100 A/μs		175	650	ns
Reverse Recovery Charge	Q _{rr}			0.6		μC

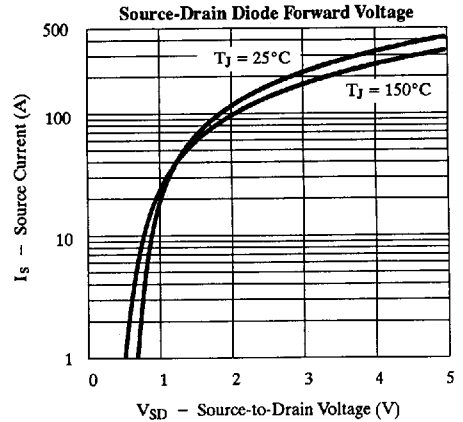
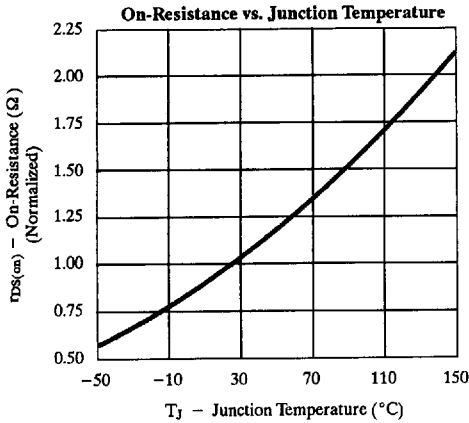
Notes:

- For design aid only; not subject to production testing.
- Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
- Independent of operating temperature.

Typical Characteristics (25°C Unless Otherwise Noted)



Typical Characteristics (25°C Unless Otherwise Noted)



Thermal Ratings

